Preferred Device

# Self-Protected FET with Temperature and Current Limit

# 65 V, 6.5 A, Single N–Channel, DPAK

HDPlus<sup>™</sup> devices are an advanced series of power MOSFETs which utilize ON Semiconductor's latest MOSFET technology process to achieve the lowest possible on–resistance per silicon area while incorporating smart features. Integrated thermal and current limits work together to provide short circuit protection. The devices feature an integrated Drain–to–Gate Clamp that enables them to withstand high energy in the avalanche mode. The Clamp also provides additional safety margin against unexpected voltage transients. Electrostatic Discharge (ESD) protection is provided by an integrated Gate–to–Source Clamp.

## Features

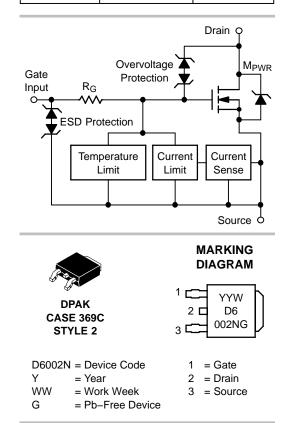
- Short Circuit Protection/Current Limit
- Thermal Shutdown with Automatic Restart
- I<sub>DSS</sub> Specified at Elevated Temperature
- Avalanche Energy Specified
- Slew Rate Control for Low Noise Switching
- Overvoltage Clamped Protection
- Pb–Free Package is Available



# **ON Semiconductor®**

#### http://onsemi.com

V <sub>DSS</sub> (Clamped)	R <sub>DS(on)</sub> TYP	I <sub>D</sub> TYP (Limited)
65 V	210 m $\Omega$	6.5 A



### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NID6002NT4	DPAK	2500/Tape & Reel
NID6002NT4G	DPAK (Pb–Free)	2500/Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

**Preferred** devices are recommended choices for future use and best overall value.

### **MOSFET MAXIMUM RATINGS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Rating	Symbol	Value	Unit	
Drain-to-Source Voltage Internally Clamped	V <sub>DSS</sub>	70	Vdc	
Gate-to-Source Voltage	V <sub>GS</sub>	±14	Vdc	
Drain Current Contin	iuous I <sub>D</sub>	Internally Limited		
Total Power Dissipation @ $T_A = 25^{\circ}C$ (Note 1) @ $T_A = 25^{\circ}C$ (Note 2)	PD	1.3 2.5	W	
Thermal Resistance Junction-to-Case Junction-to-Ambient (Note 1) Junction-to-Ambient (Note 2)	R <sub>θJC</sub> R <sub>θJA</sub> R <sub>θJA</sub>	3.0 95 50	°C/W	
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 Vdc, $V_{GS}$ = 5.0 Vdc, $I_L$ = 1.3 Apk, L = 160 mH, $R_G$ = 25 $\Omega$ ) (Note 3)	E <sub>AS</sub>	143	mJ	
Operating and Storage Temperature Range (Note 4)	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Surface mounted onto minimum pad size (100 sq/mm) FR4 PCB, 1 oz cu.
Mounted onto 1" square pad size (700 sq/mm) FR4 PCB, 1 oz cu.

3. Not subject to production test.

4. Normal pre-fault operating range. See thermal limit range conditions.

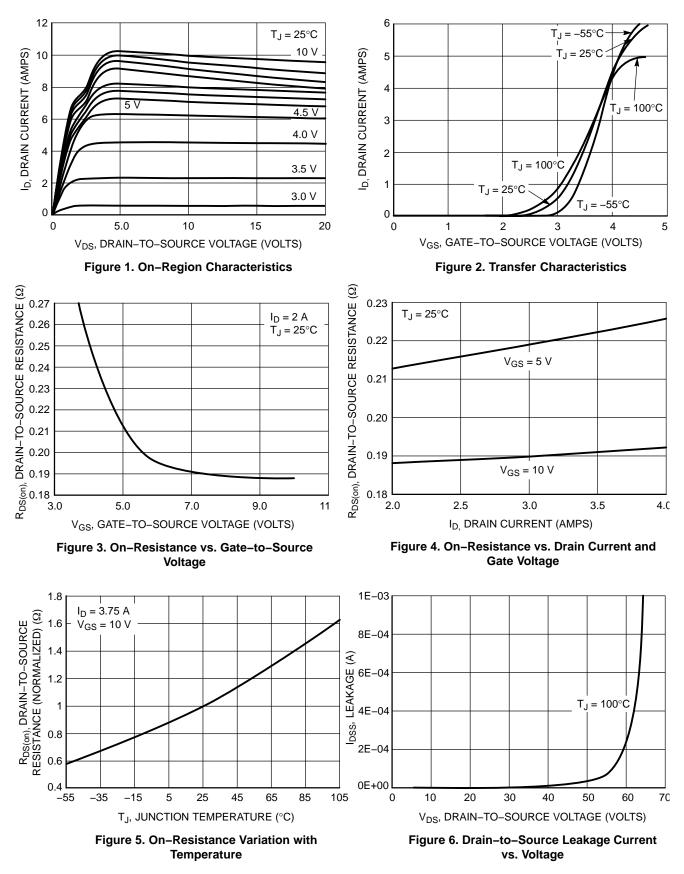
# **MOSFET ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Clamped Br $(V_{GS} = 0 \text{ V}, I_D = 2 \text{ mA})$	eakdown Voltage	V <sub>(BR)DSS</sub>	60	65	70	V
Zero Gate Voltage Drain Current $(V_{DS} = 52 \text{ V}, V_{GS} = 0 \text{ V})$		I <sub>DSS</sub>	-	27	100	μΑ
Gate Input Current (V <sub>GS</sub> = 5.0 V, V <sub>DS</sub> = 0 V)		I <sub>GSS</sub>	-	45	200	μΑ
ON CHARACTERISTICS						
Gate Threshold Voltage ( $V_{DS} = V_{GS}$ , $I_D = 150 \ \mu A$ ) Threshold Temperature Coeff	icient	V <sub>GS(th)</sub>	1.0	1.85 5.0	2.4	V -mV/°C
Static Drain-to-Source On-R (V_{GS} = 10 V, I_D = 2.0 A, T_J @		R <sub>DS(on)</sub>	-	185	210	mΩ
Static Drain-to-Source On-Resistance (Note 5) ( $V_{GS} = 5.0 \text{ V}, I_D = 2.0 \text{ A}, T_J @ 25^{\circ}\text{C}$ ) ( $V_{GS} = 5.0 \text{ V}, I_D = 2.0 \text{ A}, T_J @ 150^{\circ}\text{C}$ )		R <sub>DS(on)</sub>		210 445	240 520	mΩ
Source–Drain Forward On Voltage $(I_S = 7.0 \text{ A}, V_{GS} = 0 \text{ V})$		V <sub>SD</sub>	-	0.9	1.1	V
SWITCHING CHARACTERIS	TICS (Note 8)					
Turn-on Delay Time	$ \begin{array}{l} {\sf R}_{\sf L} = 6.6 \; \Omega, \; {\sf V}_{in} = \; 0 \; \text{to} \; 10 \; {\sf V}, \\ {\sf V}_{\sf DD} = 13.8 \; {\sf V}, \; {\sf I}_{\sf D} = 2.0 \; {\sf A}, \; 10\% \; {\sf V}_{in} \; \text{to} \; 10\% \; {\sf I}_{\sf D} \end{array} $	td <sub>(on)</sub>	-	96	-	ns
Turn-on Rise Time		t <sub>rise</sub>	-	250	-	ns
Turn-off Delay Time		td <sub>(off)</sub>	-	840	-	ns
Turn-off Fall Time	$R_L$ = 6.6 Ω, $V_{in}$ = 0 to 10 V, $V_{DD}$ = 13.8 V, $I_D$ = 2.0 A, 90% $I_D$ to 10% $I_D$	t <sub>fall</sub>	-	660	-	ns
Slew Rate ON	$R_L$ = 6.6 Ω, $V_{in}$ = 0 to 10 V, $V_{DD}$ = 13.8 V, $I_D$ = 2.0 A, 70% to 50% $V_{DD}$	$\mathrm{dV}_{\mathrm{DS}}/\mathrm{dT}_{\mathrm{on}}$	-	73	-	V/μs
Slew Rate OFF	R <sub>L</sub> = 6.6 Ω, V <sub>in</sub> = 0 to 10 V, V <sub>DD</sub> = 13.8 V, I <sub>D</sub> = 2.0 A, 50% to 70% V <sub>DD</sub>	$\mathrm{dV}_{\mathrm{DS}}/\mathrm{dT}_{\mathrm{off}}$	-	35	-	V/μs
SELF PROTECTION CHARAC	CTERISTICS (Note 6)					
Current Limit	$ \begin{array}{l} V_{DS} = 10 \ \text{V}, \ V_{GS} = 5.0 \ \text{V}, \ T_J = 25^\circ\text{C} \ (\text{Note 7}) \\ V_{DS} = 10 \ \text{V}, \ V_{GS} = 5.0 \ \text{V}, \ T_J = 130^\circ\text{C} \ (\text{Notes 7, 8}) \\ V_{DS} = 10 \ \text{V}, \ V_{GS} = 10 \ \text{V}, \ T_J = 25^\circ\text{C} \ (\text{Notes 7, 8}) \\ \end{array} $	I <sub>LIM</sub>	4.0 4.0 -	6.4 5.5 7.9	11 11 -	A
Temperature Limit (Turn-off)	V <sub>GS</sub> = 5.0 V (Note 8)	T <sub>LIM(off)</sub>	150	180	200	°C
Thermal Hysteresis	V <sub>GS</sub> = 5.0 V	$\Delta T_{LIM(on)}$	-	10	-	°C
Temperature Limit (Turn-off)	V <sub>GS</sub> = 10 V (Note 8)	T <sub>LIM(off)</sub>	150	180	200	°C
Thermal Hysteresis	V <sub>GS</sub> = 10 V	$\Delta T_{LIM(on)}$	-	20	-	°C
Input Current during Thermal Fault		I <sub>g(fault)</sub>	5.5 12	5.2 11	-	mA
SD ELECTRICAL CHARACT	TERISTICS					
Electro-Static Discharge Cap	ability	ESD				V

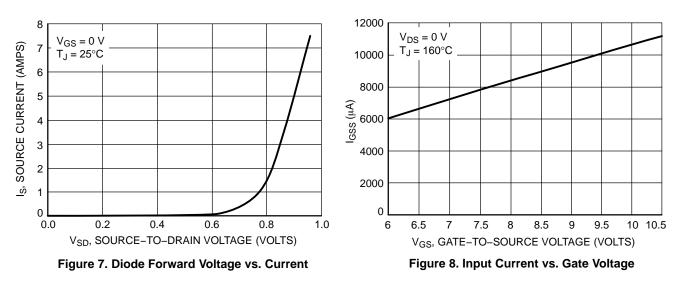
	Electro-Static Discharge Capability	ESD				V	
	Human Body Model (HBM)		8000	-	_		
	Machine Model (MM)		400	-	-		
L							1

5. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
6. Fault conditions are viewed as beyond the normal operating range of the part.
7. Current limit measured at 380 μs after gate pulse.
8. Not subject to production test.

## **TYPICAL PERFORMANCE CURVES**







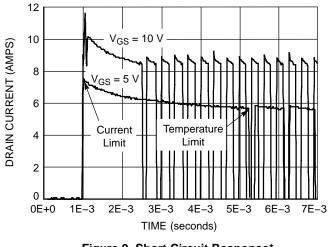


Figure 9. Short Circuit Response\*

\*(Actual thermal cycling response in short circuit dependent on device power level, thermal mounting, and ambient temperature conditions)

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